

# M5M5V416BTP,RT

**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

## 4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

### DESCRIPTION

The M5M5V416B is a family of low voltage 4-Mbit static RAMs organized as 262,144-words by 16-bit, fabricated by Mitsubishi's high-performance 0.25µm CMOS technology.

The M5M5V416B is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

M5M5V416BTP,RT are packaged in a 44-pin 400mil thin small outline package. M5M5V416BTP (normal lead bend type package), M5M5V416BRT (reverse lead bend type package), both types are very easy to design a printed circuit board.

From the point of operating temperature, the family is divided into three versions; "Standard", "W-version", and "I-version". Those are summarized in the part name table below.

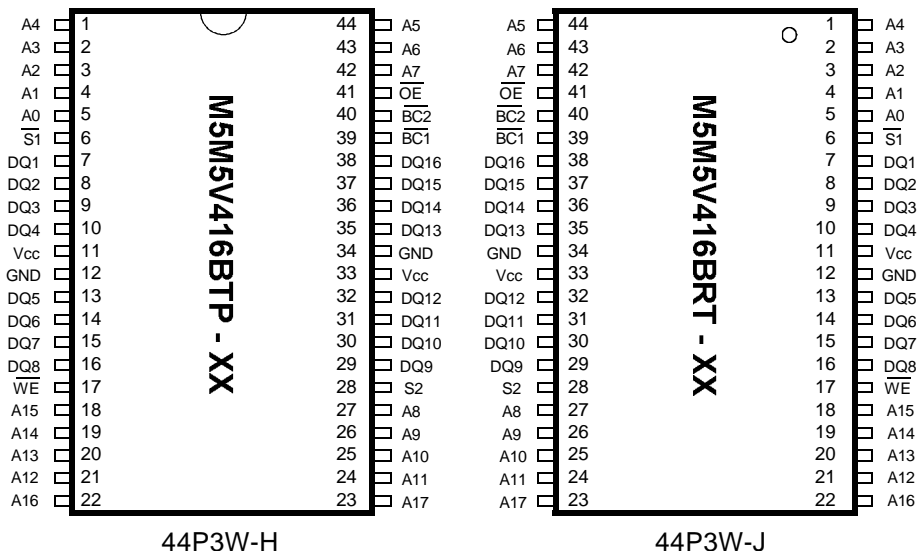
### FEATURES

- Single +2.7~+3.6V power supply
- Small stand-by current: 0.3µA(3V,typ.)
- No clocks, No refresh
- Data retention supply voltage=2.0V to 3.6V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by  $\overline{S1}$ ,  $\overline{S2}$ ,  $\overline{BC1}$  and  $\overline{BC2}$
- Common Data I/O
- Three-state outputs: OR-tie capability
- $\overline{OE}$  prevents data contention in the I/O bus
- Process technology: 0.25µm CMOS
- Package: 44 pin 400mil TSOP (II)

Version, Operating temperature	Part name	Power Supply	Access time max.	Stand-by current I <sub>cc</sub> (PD), V <sub>cc</sub> =3.0V						Active current I <sub>cc1</sub> (3.0V, typ.)
				typical *		Ratings (max.)				
				25°C	40°C	25°C	40°C	70°C	85°C	
Standard 0 ~ +70°C	M5M5V416BTP, RT -70L	2.7 ~ 3.6V	70ns	---	---	---	---	20µA	---	40mA (10MHz) 5mA (1MHz)
	M5M5V416BTP, RT -85L		85ns							
	M5M5V416BTP, RT -10L		100ns							
	M5M5V416BTP, RT -70H	2.7 ~ 3.6V	70ns	0.3µA	1µA	1µA	3µA	10µA	---	
	M5M5V416BTP, RT -85H		85ns							
	M5M5V416BTP, RT -10H		100ns							
W-version -20 ~ +85°C	M5M5V416BTP, RT -70LW	2.7 ~ 3.6V	70ns	---	---	---	---	20µA	40µA	
	M5M5V416BTP, RT -85LW		85ns							
	M5M5V416BTP, RT -10LW		100ns							
	M5M5V416BTP, RT -70HW	2.7 ~ 3.6V	70ns	0.3µA	1µA	1µA	3µA	10µA	20µA	
	M5M5V416BTP, RT -85HW		85ns							
	M5M5V416BTP, RT -10HW		100ns							
I-version -40 ~ +85°C	M5M5V416BTP, RT -70LI	2.7 ~ 3.6V	70ns	---	---	---	---	20µA	40µA	
	M5M5V416BTP, RT -85LI		85ns							
	M5M5V416BTP, RT -10LI		100ns							
	M5M5V416BTP, RT -70HI	2.7 ~ 3.6V	70ns	0.3µA	1µA	1µA	3µA	10µA	20µA	
	M5M5V416BTP, RT -85HI		85ns							
	M5M5V416BTP, RT -10HI		100ns							

\* "typical" parameter is sampled, not 100% tested.

### PIN CONFIGURATION



Pin	Function
A0 ~ A17	Address input
DQ1 ~ DQ16	Data input / output
$\overline{S1}$	Chip select input 1
$\overline{S2}$	Chip select input 2
$\overline{W}$	Write control input
$\overline{OE}$	Output enable input
$\overline{BC1}$	Lower Byte (DQ1 ~ 8)
$\overline{BC2}$	Upper Byte (DQ9 ~ 16)
V <sub>cc</sub>	Power supply
GND	Ground supply

Outline: 44P3W-H/J  
NC: No Connection



# M5M5V416BTP,RT

**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

## ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Units
V <sub>CC</sub>	Supply voltage	With respect to GND	-0.5* ~ +4.6	V
V <sub>I</sub>	Input voltage	With respect to GND	-0.5* ~ V <sub>CC</sub> + 0.5	
V <sub>O</sub>	Output voltage	With respect to GND	0 ~ V <sub>CC</sub>	
P <sub>d</sub>	Power dissipation	T <sub>a</sub> =25°C	700	mW
T <sub>a</sub>	Operating temperature	Standard (-L, -H)	0 ~ +70	°C
		W-version (-LW, -HW)	-20 ~ +85	
		I-version (-LI, -HI)	-40 ~ +85	
T <sub>stg</sub>	Storage temperature		-65 ~ +150	°C

\* -3.0V in case of AC (Pulse width ≤ 30ns)

## DC ELECTRICAL CHARACTERISTICS

(V<sub>CC</sub>=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units		
			Min	Typ	Max			
V <sub>IH</sub>	High-level input voltage		2.2		V <sub>CC</sub> +0.3V	V		
V <sub>IL</sub>	Low-level input voltage		-0.3*		0.6			
V <sub>OH1</sub>	High-level output voltage 1	I <sub>OH</sub> = -0.5mA	2.4					
V <sub>OH2</sub>	High-level output voltage 2	I <sub>OH</sub> = -0.05mA	V <sub>CC</sub> -0.5V					
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> =2mA			0.4			
I <sub>I</sub>	Input leakage current	V <sub>I</sub> =0 ~ V <sub>CC</sub>			±1	μA		
I <sub>O</sub>	Output leakage current	$\overline{BC1}$ and $\overline{BC2}$ =V <sub>IH</sub> or $\overline{S1}$ =V <sub>IH</sub> or $\overline{S2}$ =V <sub>IH</sub> or $\overline{OE}$ =V <sub>IH</sub> , V <sub>I/O</sub> =0 ~ V <sub>CC</sub>			±1	μA		
I <sub>CC1</sub>	Active supply current (AC, MOS level)	$\overline{BC1}$ and $\overline{BC2}$ ≤ 0.2V, $\overline{S1}$ ≤ 0.2V, $\overline{S2}$ ≥ V <sub>CC</sub> -0.2V other inputs ≤ 0.2V or ≥ V <sub>CC</sub> -0.2V Output - open (duty 100%)	f = 10MHz	-	40	50	mA	
			f = 1MHz	-	5	10		
I <sub>CC2</sub>	Active supply current (AC, TTL level)	$\overline{BC1}$ and $\overline{BC2}$ =V <sub>IL</sub> , $\overline{S1}$ =V <sub>IL</sub> , $\overline{S2}$ =V <sub>IH</sub> other pins =V <sub>IH</sub> or V <sub>IL</sub> Output - open (duty 100%)	f = 10MHz	-	40	50	mA	
			f = 1MHz	-	5	10		
I <sub>CC3</sub>	Stand by supply current (AC, MOS level)	< 1 > $\overline{S1}$ ≥ V <sub>CC</sub> - 0.2V, other inputs = 0 ~ V <sub>CC</sub> < 2 > $\overline{S2}$ ≤ 0.2V, other inputs = 0 ~ V <sub>CC</sub> < 3 > $\overline{BC1}$ and $\overline{BC2}$ ≥ V <sub>CC</sub> - 0.2V $\overline{S1}$ ≤ 0.2V, $\overline{S2}$ ≥ V <sub>CC</sub> - 0.2V Other inputs=0~V <sub>CC</sub>	-LW, -LI	+70 ~ +85°C	-	-	48	μA
			-L, -LW, -LI	+70°C	-	-	24	
			-HW, -HI	+70 ~ +85°C	-	-	24	
			-H, -HW, -HI	+40 ~ +70°C	-	-	12	
				+25 ~ +40°C	-	1	3.6	
			-H	0 ~ +25°C	-	0.3	1.2	
			-HW	-20 ~ +25°C	-	0.3	1.2	
-HI	-40 ~ +25°C	-	0.3	1.2				
I <sub>CC4</sub>	Stand by supply current (AC, TTL level)	$\overline{BC1}$ and $\overline{BC2}$ =V <sub>IH</sub> or $\overline{S1}$ =V <sub>IH</sub> or $\overline{S2}$ =V <sub>IL</sub> Other inputs=0 ~ V <sub>CC</sub>	-	-	0.5	mA		

Note 1: Direction for current flowing into IC is indicated as positive (no mark)

\* -3.0V in case of AC (Pulse width ≤ 30ns)

Note 2: Typical value is for V<sub>CC</sub>=3.0V and T<sub>a</sub>=25°C

## CAPACITANCE

(V<sub>CC</sub>=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units
			Min	Typ	Max	
C <sub>I</sub>	Input capacitance	V <sub>I</sub> =GND, V <sub>I</sub> =25mVrms, f=1MHz			10	pF
C <sub>O</sub>	Output capacitance	V <sub>O</sub> =GND, V <sub>O</sub> =25mVrms, f=1MHz			10	

# M5M5V416BTP,RT

**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

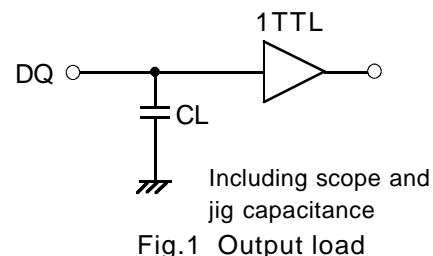
## 4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

### AC ELECTRICAL CHARACTERISTICS

(V<sub>CC</sub>=2.7 ~ 3.6V, unless otherwise noted)

#### (1) TEST CONDITIONS

Supply voltage	2.7V~3.6V
Input pulse	V <sub>IH</sub> =2.4V, V <sub>IL</sub> =0.4V
Input rise time and fall time	5ns
Reference level	V <sub>OH</sub> =V <sub>OL</sub> =1.5V Transition is measured ±500mV from steady state voltage.(for t <sub>en</sub> ,t <sub>dis</sub> )
Output loads	Fig.1,CL=30pF CL=5pF (for t <sub>en</sub> ,t <sub>dis</sub> )



#### (2) READ CYCLE

Symbol	Parameter	Limits						Units
		70L,70H,70LW 70HW,70LI,70HI		85L,85H,85LW 85HW,85LI,85HI		10L,10H,10LW 10HW,10LI,10HI		
		Min	Max	Min	Max	Min	Max	
t <sub>CR</sub>	Read cycle time	70		85		100		ns
t <sub>a(A)</sub>	Address access time		70		85		100	ns
t <sub>a(S1)</sub>	Chip select 1 access time		70		85		100	ns
t <sub>a(S2)</sub>	Chip select 2 access time		70		85		100	ns
t <sub>a(BC1)</sub>	Byte control 1 access time		70		85		100	ns
t <sub>a(BC2)</sub>	Byte control 2 access time		70		85		100	ns
t <sub>a(OE)</sub>	Output enable access time		35		45		50	ns
t <sub>dis(S1)</sub>	Output disable time after S1 high		25		30		35	ns
t <sub>dis(S2)</sub>	Output disable time after S2 low		25		30		35	ns
t <sub>dis(BC1)</sub>	Output disable time after BC1 high		25		30		35	ns
t <sub>dis(BC2)</sub>	Output disable time after BC2 high		25		30		35	ns
t <sub>dis(OE)</sub>	Output disable time after OE high		25		30		35	ns
t <sub>en(S1)</sub>	Output enable time after S1 low	10		10		10		ns
t <sub>en(S2)</sub>	Output enable time after S2 high	10		10		10		ns
t <sub>en(BC1)</sub>	Output enable time after BC1 low	10		10		10		ns
t <sub>en(BC2)</sub>	Output enable time after BC2 low	10		10		10		ns
t <sub>en(OE)</sub>	Output enable time after OE low			5		5		ns
t <sub>v(A)</sub>	Data valid time after address	10		10		10		ns

#### (3) WRITE CYCLE

Symbol	Parameter	Limits						Units
		70L,70H,70LW 70HW,70LI,70HI		85L,85H,85LW 85HW,85LI,85HI		10L,10H,10LW 10HW,10LI,10HI		
		Min	Max	Min	Max	Min	Max	
t <sub>cw</sub>	Write cycle time	70		85		100		ns
t <sub>w(W)</sub>	Write pulse width	55		60		75		ns
t <sub>su(A)</sub>	Address setup time	0		0		0		ns
t <sub>su(A-WH)</sub>	Address setup time with respect to $\overline{W}$	65		70		85		ns
t <sub>su(BC1)</sub>	Byte control 1 setup time	65		70		85		ns
t <sub>su(BC2)</sub>	Byte control 2 setup time	65		70		85		ns
t <sub>su(S1)</sub>	Chip select 1 setup time	65		70		85		ns
t <sub>su(S2)</sub>	Chip select 2 setup time	65		70		85		ns
t <sub>su(D)</sub>	Data setup time	35		35		40		ns
t <sub>h(D)</sub>	Data hold time	0		0		0		ns
t <sub>rec(W)</sub>	Write recovery time	0		0		0		ns
t <sub>dis(W)</sub>	Output disable time from $\overline{W}$ low		25		30		35	ns
t <sub>dis(OE)</sub>	Output disable time from $\overline{OE}$ high		25		30		35	ns
t <sub>en(W)</sub>	Output enable time from $\overline{W}$ high	5		5		5		ns
t <sub>en(OE)</sub>	Output enable time from $\overline{OE}$ low	5		5		5		ns

# M5M5V416BTP,RT

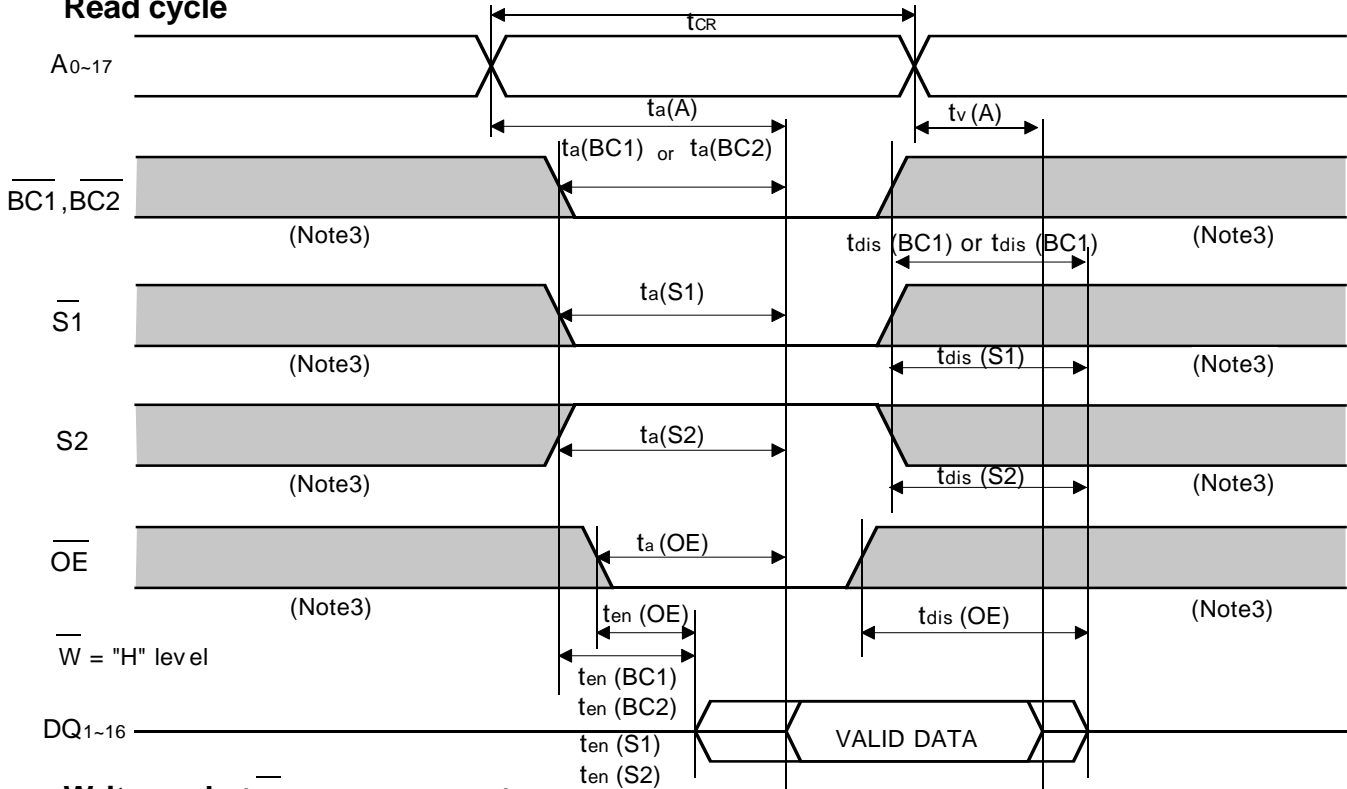
**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

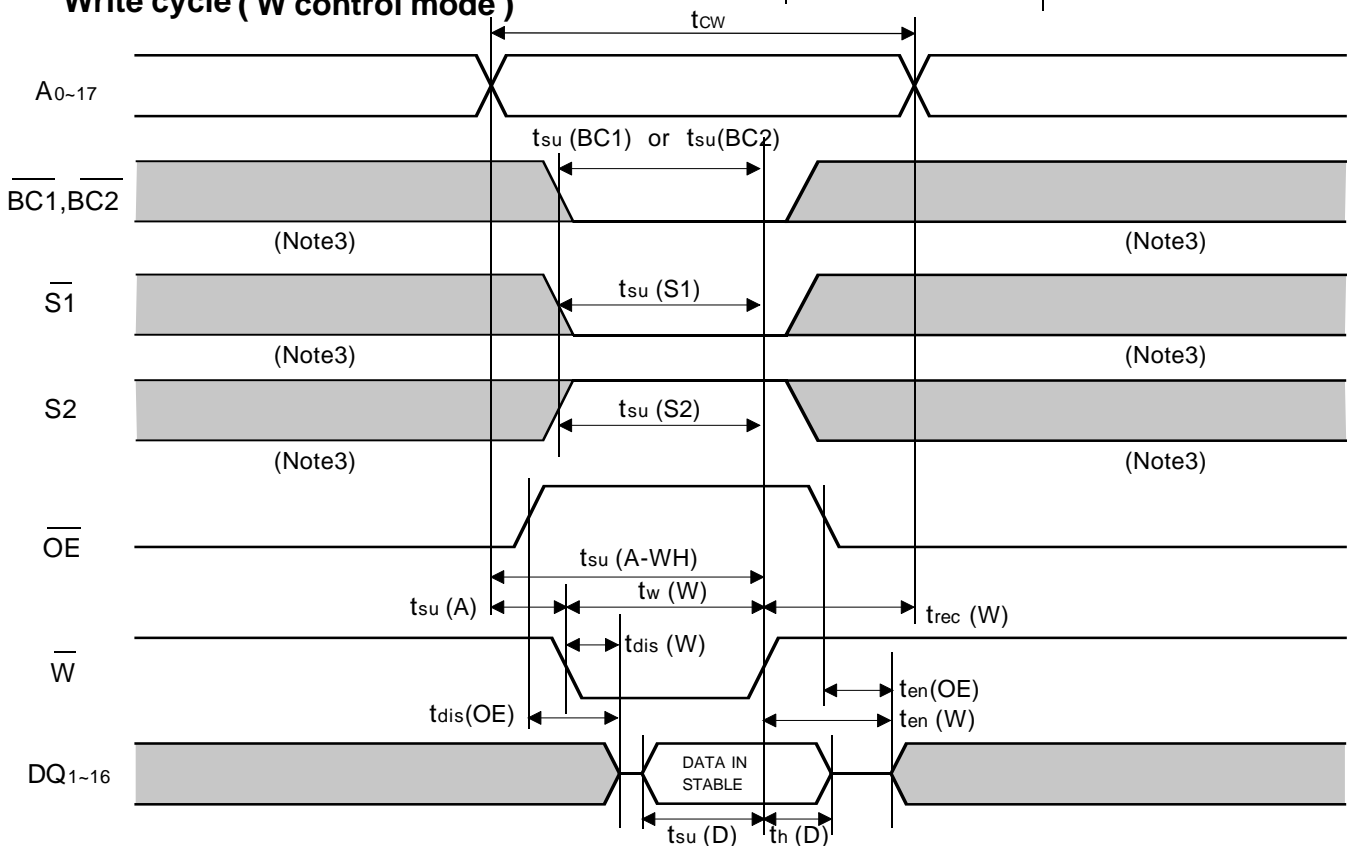
4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

## (4) TIMING DIAGRAMS

### Read cycle



### Write cycle (W control mode)

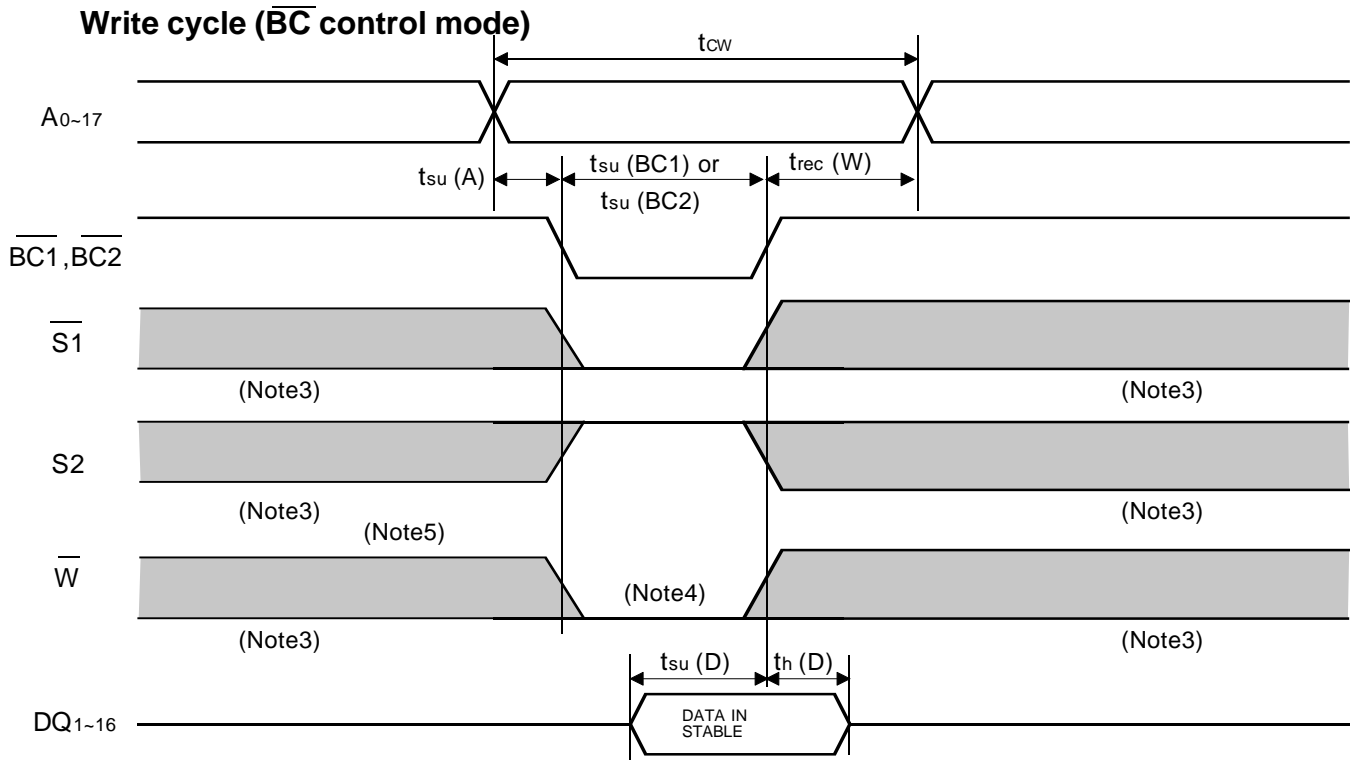


# M5M5V416BTP,RT

**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM



Note 3: Hatching indicates the state is "don't care".

Note 4: A Write occurs during  $\overline{S1}$  low, S2 high overlaps  $\overline{BC1}$  and/or  $\overline{BC2}$  low and  $\overline{W}$  low.

Note 5: When the falling edge of  $\overline{W}$  is simultaneously or prior to the falling edge of  $\overline{BC1}$  and/or  $\overline{BC2}$  or the falling edge of  $\overline{S1}$  or rising edge of S2, the outputs are maintained in the high impedance state.

Note 6: Don't apply inverted phase signal externally when DQ pin is in output mode.

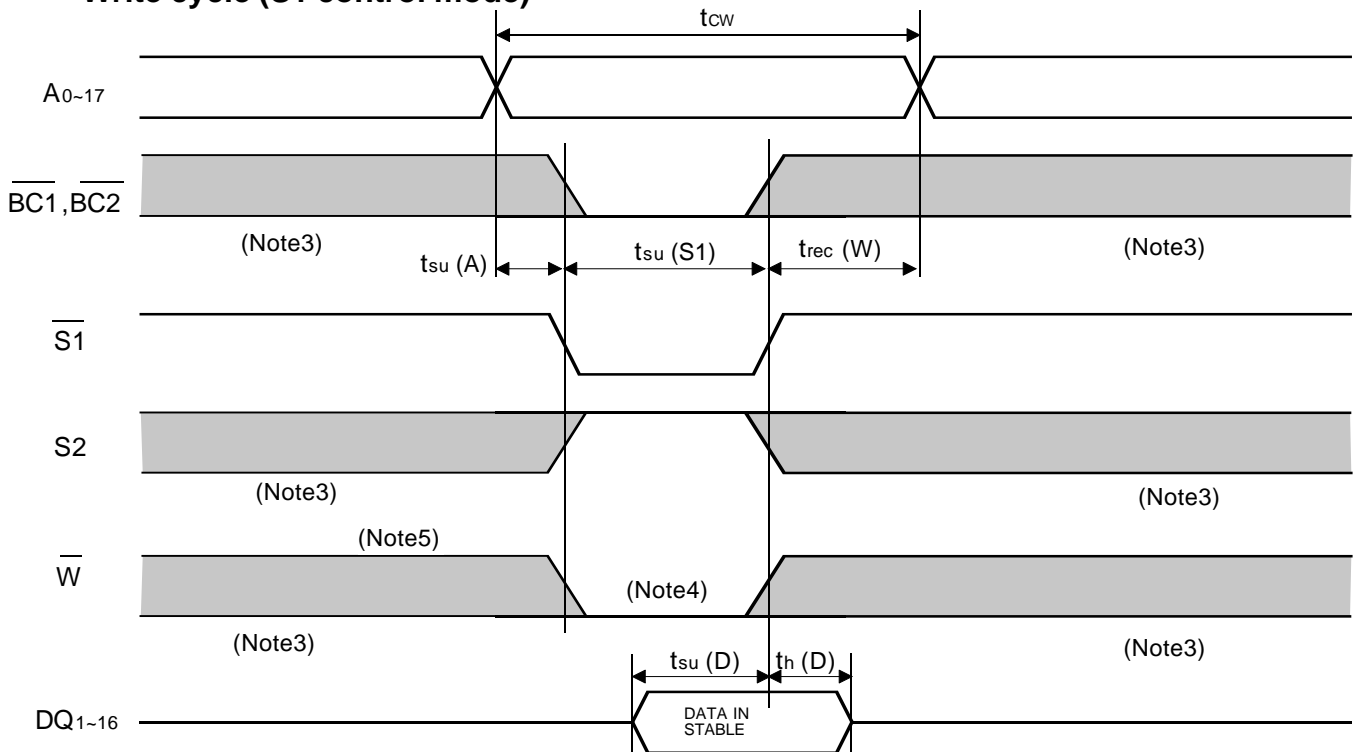
# M5M5V416BTP,RT

**PRELIMINARY**

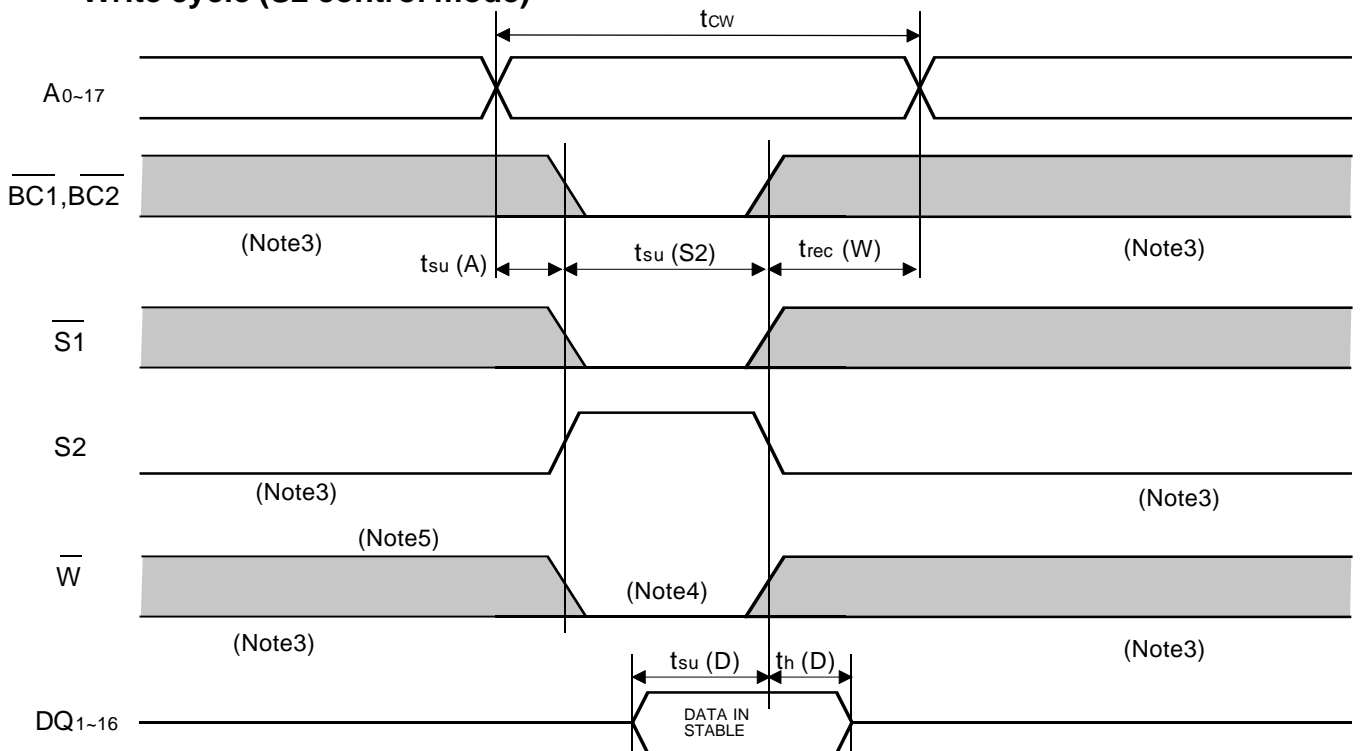
Notice: This is not a final specification.  
Some parametric limits are subject to change

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

## Write cycle ( $\overline{S1}$ control mode)



## Write cycle ( $S2$ control mode)



# M5M5V416BTP,RT

**PRELIMINARY**

Notice: This is not a final specification.  
Some parametric limits are subject to change

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

## POWER DOWN CHARACTERISTICS

### (1) ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits			Units		
			Min	Typ	Max			
V <sub>CC</sub> (PD)	Power down supply voltage		2.0			V		
V <sub>I</sub> (BC)	Byte control input $\overline{BC1}$ & $\overline{BC2}$		2.0			V		
V <sub>I</sub> ( $\overline{S1}$ )	Chip select input $\overline{S1}$		2.0			V		
V <sub>I</sub> (S2)	Chip select input S2				0.2	V		
I <sub>CC</sub> (PD)	Power down supply current	V <sub>CC</sub> =3.0V 1) $\overline{BC1}$ and $\overline{BC2} \geq V_{CC}-0.2V$ $\overline{S1} \leq 0.2V$ or $S2 \geq V_{CC}-0.2V$ other inputs=0~3V 2) $\overline{S1} \geq V_{CC}-0.2V$ other inputs=0~3V 3) $S2 \leq 0.2V$ other inputs=0~3V	-LW, -LI	+70 ~ +85°C	-	-	40	μA
			-L, -LW, -LI	+70°C	-	-	20	μA
			-HW, -HI	+70 ~ +85°C	-	-	20	μA
			-H, -HW, -HI	+40 ~ +70°C	-	-	10	μA
				+25 ~ +40°C	-	1	3	μA
			-H	0 ~ +25°C	-	0.3	1	μA
			-HW	-20 ~ +25°C	-	0.3	1	μA
-HI	-40 ~ +25°C	-	0.3	1	μA			

Typical value is for Ta=25°C

### (2) TIMING REQUIREMENTS

Symbol	Parameter	Test conditions	Limits			Units
			Min	Typ	Max	
t <sub>su</sub> (PD)	Power down set up time		0			ns
t <sub>rec</sub> (PD)	Power down recovery time		5			ms

### (3) TIMING DIAGRAM

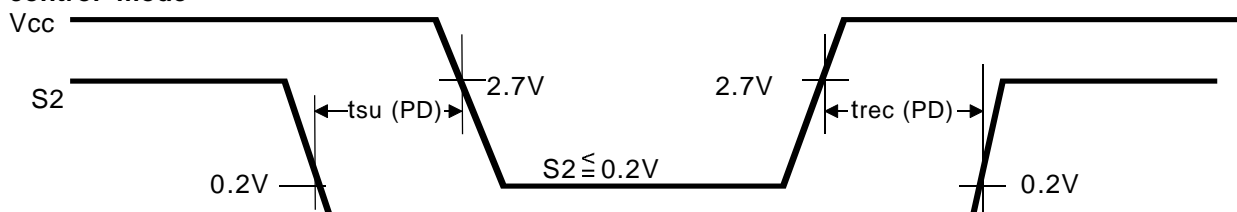
#### BC control mode



#### S1 control mode



#### S2 control mode





**M5M5V416BTP,RT****PRELIMINARY**Notice: This is not a final specification.  
Some parametric limits are subject to change**4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM**

---

**Revision History**

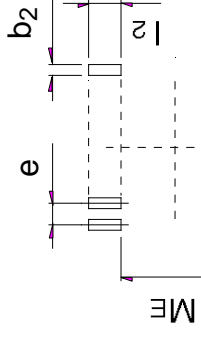
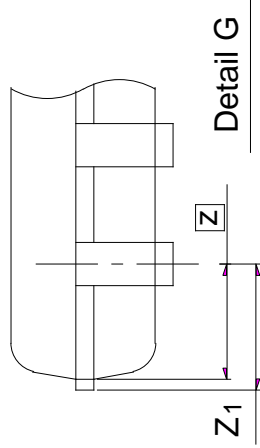
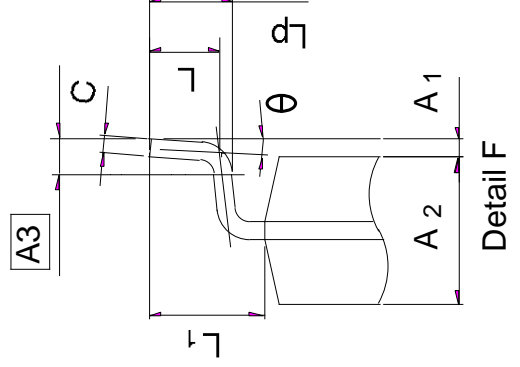
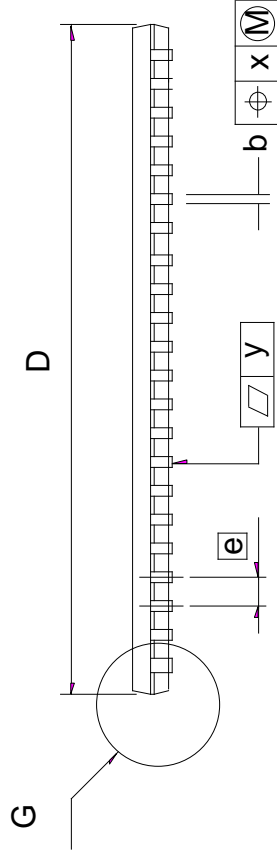
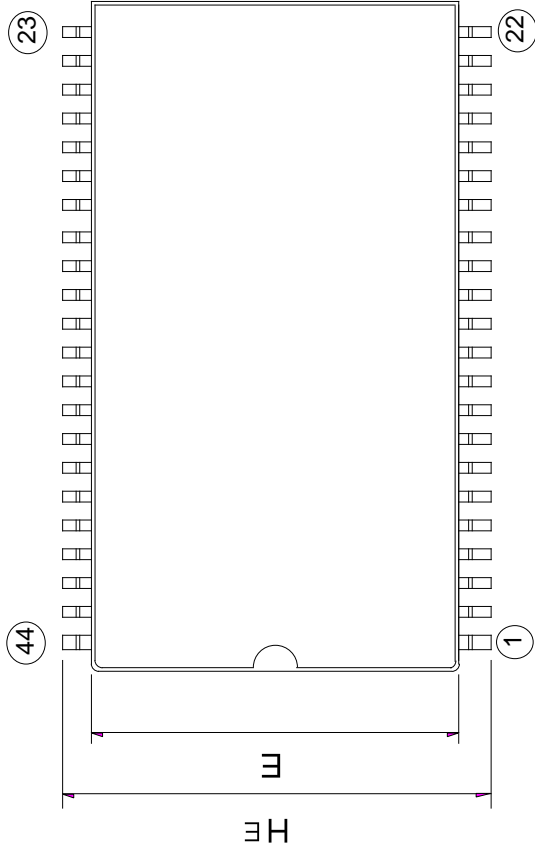
<u>Revision No.</u>	<u>History</u>	<u>Date</u>	<u>Remark</u>
P01	The first edition	'98 . 07 . 07	Preliminary
P02	Pin#28: NC --> S2	'98 . 07 . 14	Preliminary
P03	Font problem fixed	'98 . 08 . 27	Preliminary
P04	70ns version added	'98 . 12 . 16	Preliminary

# 44P3W-H

# Plastic 44pin 400mil TSOP(II)

EIAJ Package Code	JEDEC Code	Weight(g)	Lead Material
TSOPII44-P-400-0.80	—	0.47	Alloy 42

Scale: 3/1



## Recommended Mount Pad

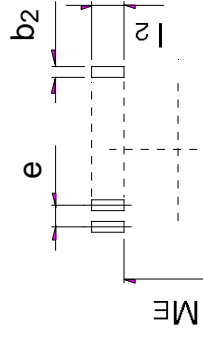
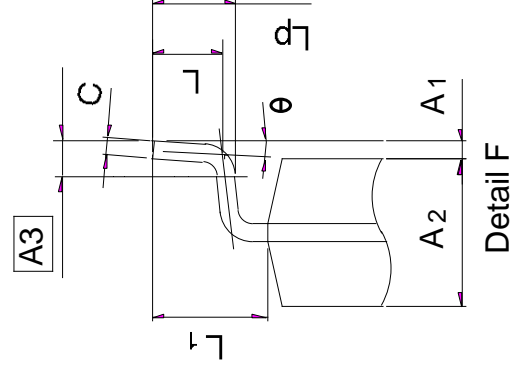
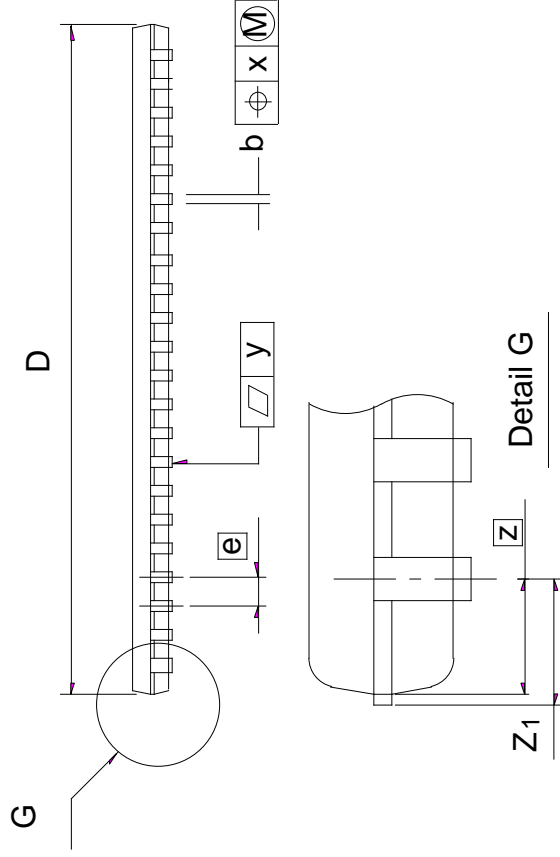
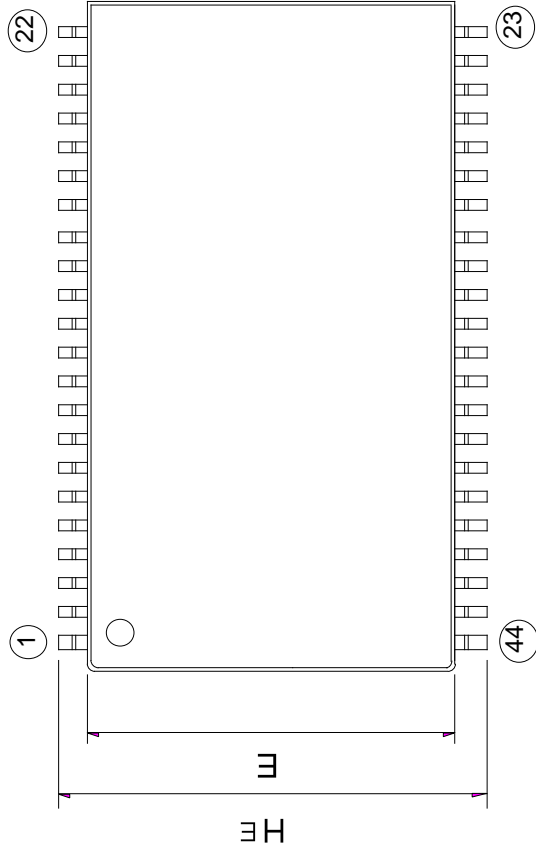
Symbol	Dimension in Millimeters	
	Min	Max
A	—	1.2
A1	0.05	0.2
A2	—	1.0
b	0.3	0.35
c	0.105	0.125
D	18.31	18.41
E	10.06	10.16
e	—	0.8
HE	11.56	11.76
L	0.4	0.5
L1	—	0.8
Lp	0.45	0.6
A3	—	0.25
Z	—	0.805
Z1	—	0.955
x	—	0.16
y	—	0.1
$\theta$	0°	10°
ME	—	10.36
I2	0.9	—
b2	—	0.5

# 44P3W-J

# Plastic 44pin 400mil TSOP(II)

EIAJ Package Code	JEDEC Code	Weight(g)	Lead Material
TSOPII44-P-400-0.80	—	0.47	Alloy 42

Scale: 3/1



Recommended Mount Pad

Symbol	Dimension in Millimeters		
	Min	Nom	Max
A	—	—	1.2
A1	0.05	0.125	0.2
A2	—	1.0	—
b	0.3	0.35	0.45
c	0.105	0.125	0.175
D	18.31	18.41	18.51
E	10.06	10.16	10.26
e	—	0.8	—
HE	11.56	11.76	11.96
L	0.4	0.5	0.6
L1	—	0.8	—
Lp	0.45	0.6	0.75
A3	—	0.25	—
Z	—	0.805	—
Z1	—	—	0.955
x	—	—	0.16
y	—	—	0.1
theta	0°	—	10°
ME	—	10.36	—
l2	0.9	—	—
b2	—	0.5	—